P/1805-17

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of	New York, New York
Markus Turtinen, et al.	Date: December 18, 2006
Serial No.: 10/526,831	Group Art Unit: 2856
Filed: July 20, 2005	Examiner: ---

For: CHARACTERISATION OF PAPER

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Sir:

Submitted herewith is a copy of art together with a form listing the same for the convenience of the Examiner.

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Robert C. Faber

_____
Name of applicant, assignee or
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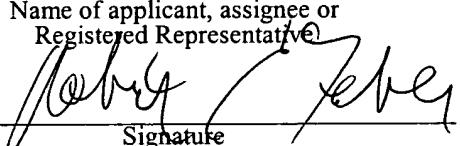
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Signature
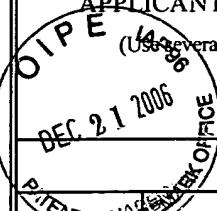December 18, 2006
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Date of Signature

Respectfully submitted,

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Enclosures

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APPLICANT'S ART CITATION (Use several sheets if necessary)	Application 10/526,831		OFGS File No. P/1805-17		
	Applicant Markus Turtinen, et al.				
	Filing Date July 20, 2005		Group Art Unit 2856		

U.S. PATENT DOCUMENTS (not submitted for applications filed after 6/30/03)

Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate
	US-					
	US-					
	US-					
	US-					
	US-					
	US-					
	US-					

FOREIGN PATENT DOCUMENTS

	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation Yes	Translation No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

		Jukka Iivarinen (2000) Surface Defect Detection with Histogram-Based Texture Features, Helsinki University of Technology, Laboratory of Computer and Information Science.
		Jukka Iivarinen, et al. (1998) An Adaptive Texture and Shape Based Defect Classification, Pattern Recognition, Proceedings, PP. 117-122.
		Timo Ojala, et al., Gray Scale and Rotation Invariant Texture Classification with Local Binary Patterns, IEEE Transactions on Pattern Analysis and Machine Intelligence, Vol. 24, No. 7.

Examiner	Date Considered

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

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